

Notice of References Cited

Application/Control No.

10/567,622

Applicant(s)/Patent Under
Reexamination
FUKUDA, KUNIO

Examiner

QUANG PHAM

Art Unit

2612

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,671,254 A	09-1997	Nagata et al.	375/326
*	B	US-5,940,006 A	08-1999	MacLellan et al.	340/10.1
*	C	US-6,122,329 A	09-2000	Zai et al.	375/329
*	D	US-2001/0001758 A1	05-2001	Greeff et al.	455/41
*	E	US-2001/0007335 A1	07-2001	Tuttle et al.	235/492
*	F	US-6,262,767 B1	07-2001	Wakui, Yoshio	348/211.99
*	G	US-2001/0055373 A1	12-2001	Yamashita, Makoto	379/90.01
*	H	US-6,351,645 B1	02-2002	Suzuki et al.	455/458
*	I	US-2002/0065576 A1	05-2002	Beaucour, Jerome	700/225
*	J	US-6,408,095 B1	06-2002	Maeda et al.	382/232
*	K	US-6,400,903 B1	06-2002	Conoval, Paul	396/56
*	L	US-2002/0090910 A1	07-2002	Takemura, Hideki	455/3.05
*	M	US-2002/0101619 A1	08-2002	Tsubaki et al.	358/302

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
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NON-PATENT DOCUMENTS

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	U	
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	X	

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0127019 A1	09-2002	Ogasawara, Akira	396/661
*	B	US-2002/0154221 A1	10-2002	Ishimaru, Toshiaki	348/207.1
*	C	US-2003/0036397 A1	02-2003	TAKAHASHI, TAKUMI	455/502
*	D	US-6,545,709 B2	04-2003	Takei et al.	348/222.1
*	E	US-2003/0103144 A1	06-2003	Sesek et al.	348/207.1
*	F	US-6,686,829 B1	02-2004	Hohberger et al.	340/10.1
*	G	US-6,720,866 B1	04-2004	Sorrells et al.	340/10.4
*	H	US-2004/0183918 A1	09-2004	Squilla et al.	348/211.2
*	I	US-7,019,639 B2	03-2006	Stilp, Louis A.	340/531
*	J	US-7,110,755 B2	09-2006	Shibasaki et al.	455/420
*	K	US-7,280,851 B2	10-2007	Oba et al.	455/566
*	L	US-7,304,682 B2	12-2007	Nihei et al.	348/362
*	M	US-7,315,522 B2	01-2008	Wood, Jr., Clifton W.	370/312

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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	U					
	V					
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	X					

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,362,371 B1	04-2008	Tanaka et al.	348/373
*	B	US-2008/0239083 A1	10-2008	Kusaka et al.	348/207.1
*	C	US-7,443,420 B2	10-2008	Maeda, Masamine	348/207.2
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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	M	US-			

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	N					
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